

**General Description**

- Latest Trench Power MOSFET technology
- Very Low  $R_{DS(on)}$  at 4.5V  $V_{GS}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

**Product Summary**

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	46A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 5.9mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$ )	< 11.9mΩ

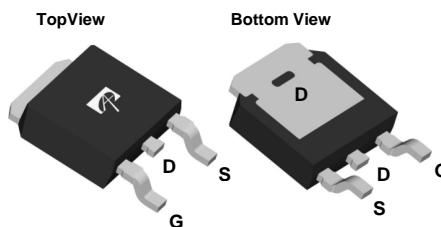
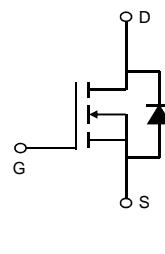
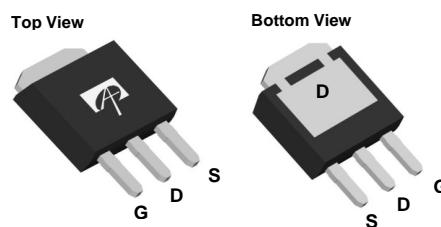
**Application**

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial

100% UIS Tested

100%  $R_g$  Tested

TO252 DPAK: AOD514

TO251A IPAK: AOI514  
TO251B (IPAK short lead): AOY514
**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	46	A
$T_C=100^\circ C$		36	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	163	
Continuous Drain Current	$I_{DSM}$	17	A
$T_A=70^\circ C$		13	
Avalanche Current <sup>C</sup>	$I_{AS}$	25	A
Avalanche energy $L=0.1mH$ <sup>C</sup>	$E_{AS}$	31	mJ
$V_{DS}$ Spike	$V_{SPIKE}$	36	V
Power Dissipation <sup>B</sup>	$P_D$	50	W
$T_C=100^\circ C$		25	
Power Dissipation <sup>A</sup>	$P_{DSM}$	2.5	W
$T_A=70^\circ C$		1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

**Thermal Characteristics**

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	16	20	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		41	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	2.5	3	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.6	2	2.4	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		4.3	5.9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		5.4	7.5	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		91		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				46	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		1187		pF
$C_{\text{oss}}$	Output Capacitance			483		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			60		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.7	1.5	2.3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		18		nC
$Q_g(4.5\text{V})$	Total Gate Charge			8.8		nC
$Q_{\text{gs}}$	Gate Source Charge			4.1		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.6		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		7.3		ns
$t_r$	Turn-On Rise Time			10.5		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			21.8		ns
$t_f$	Turn-Off Fall Time			5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		14.7		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		24		nC

A. The value of  $R_{\text{DSM}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{DSM}}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $175^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

D. The  $R_{\text{JA,C}}$  is the sum of the thermal impedance from junction to case  $R_{\text{AUC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.



**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

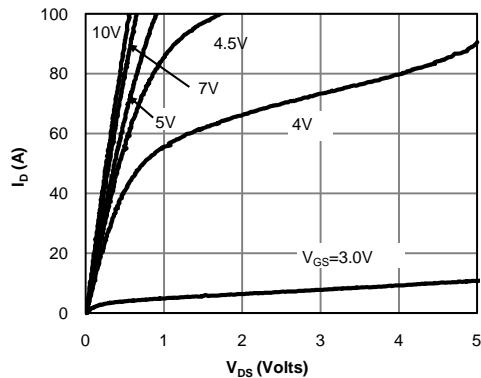


Fig 1: On-Region Characteristics (Note E)

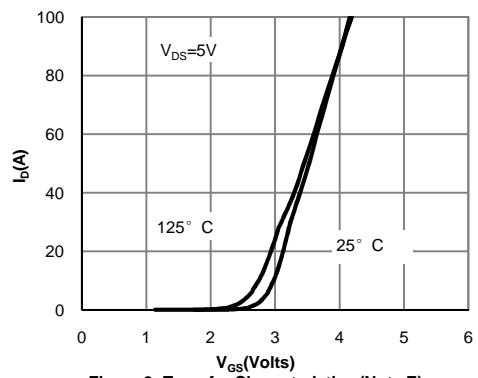


Figure 2: Transfer Characteristics (Note E)

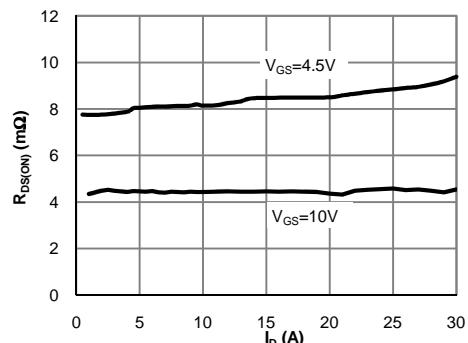


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

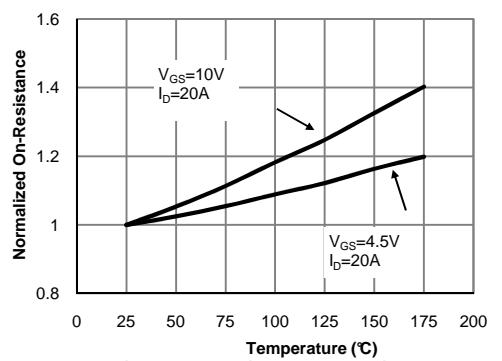


Figure 4: On-Resistance vs. Junction Temperature (Note E)

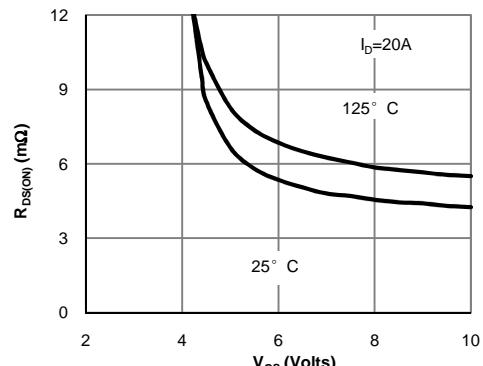


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

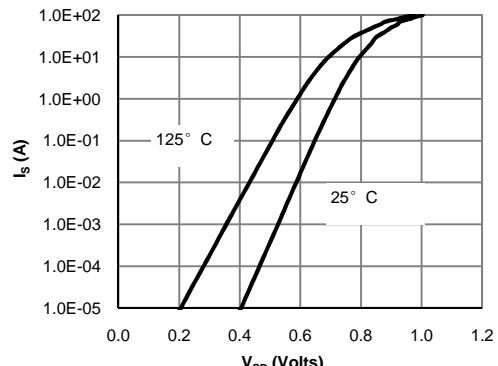


Figure 6: Body-Diode Characteristics (Note E)



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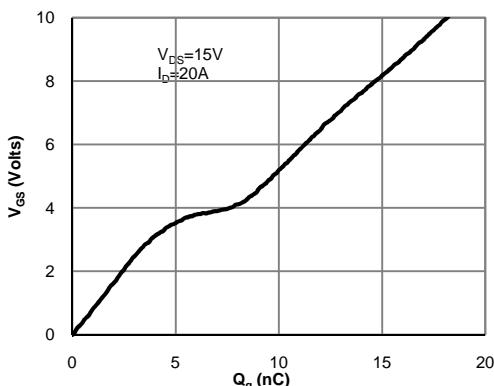


Figure 7: Gate-Charge Characteristics

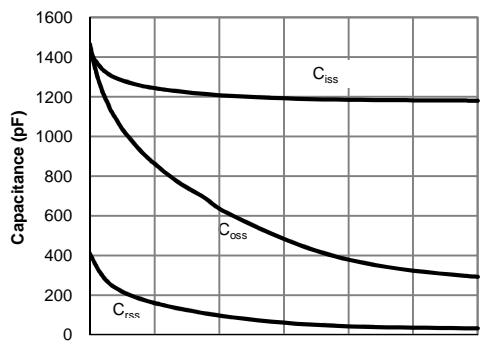


Figure 8: Capacitance Characteristics

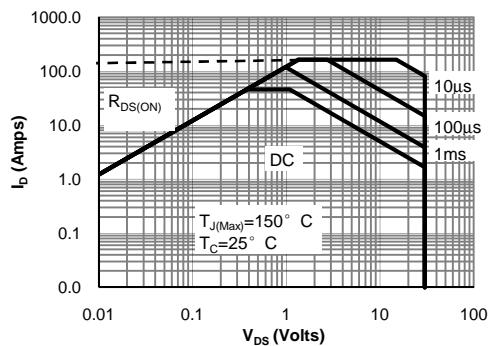


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

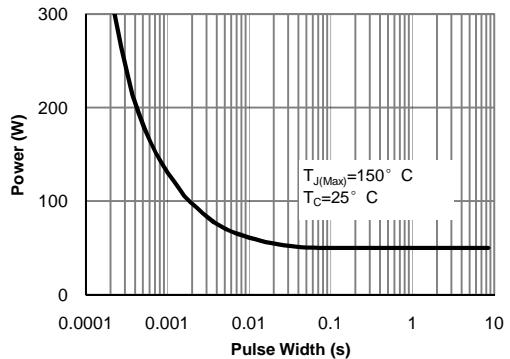


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

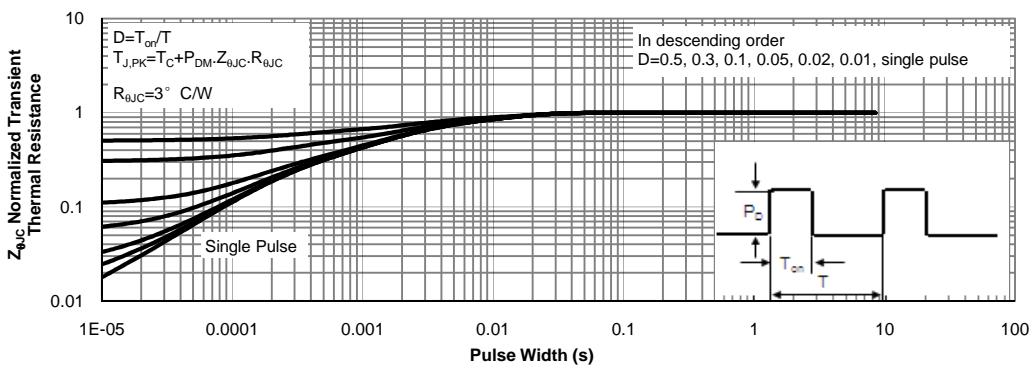
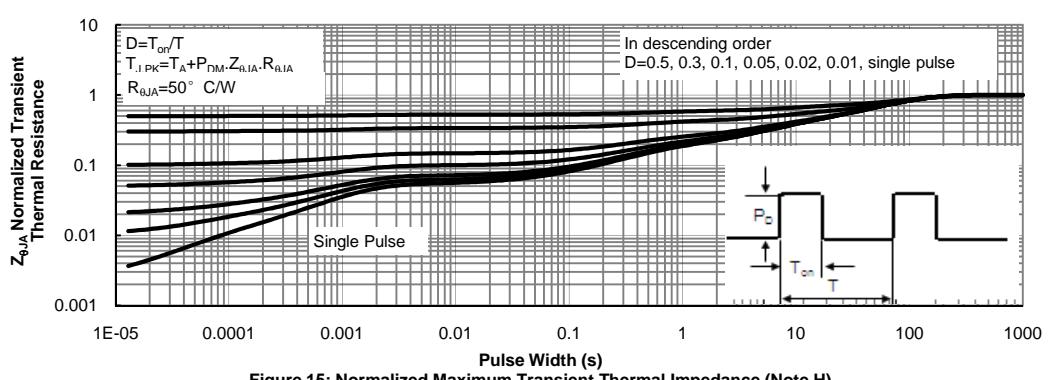
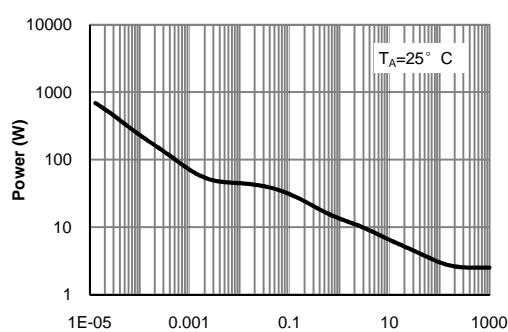
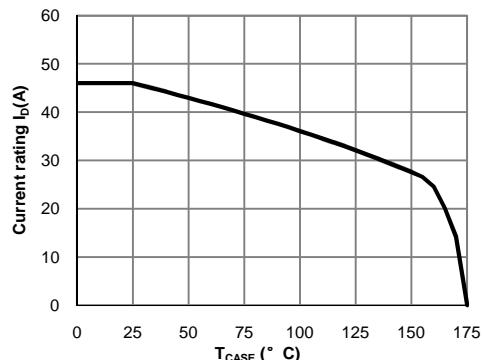
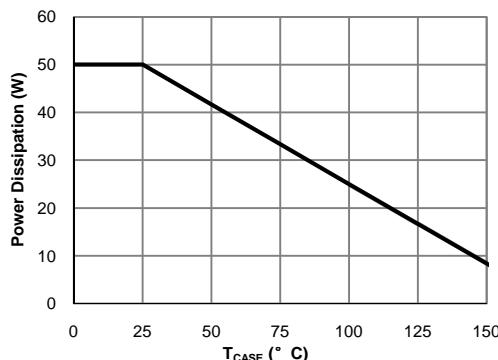


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

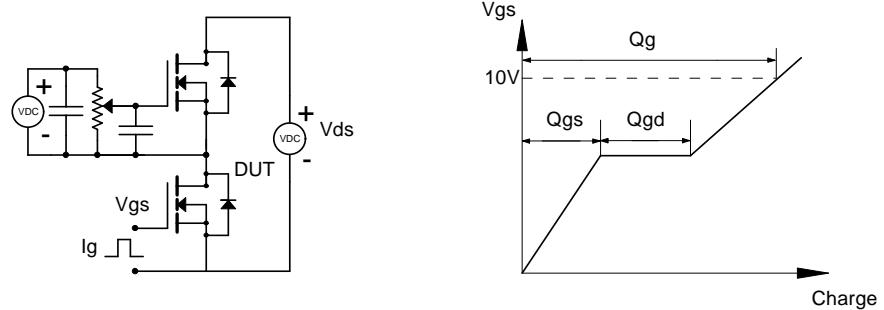


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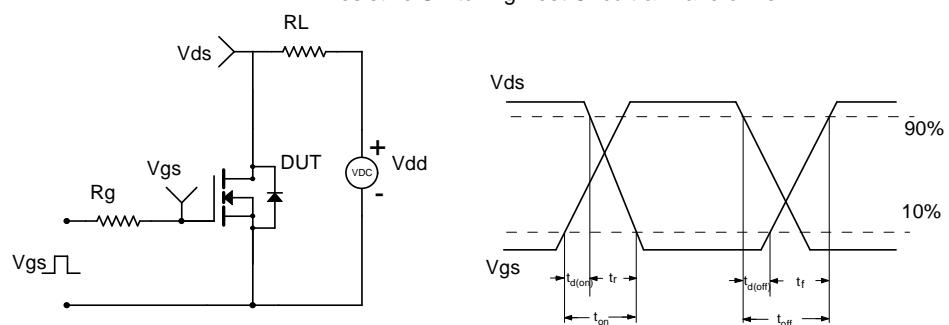




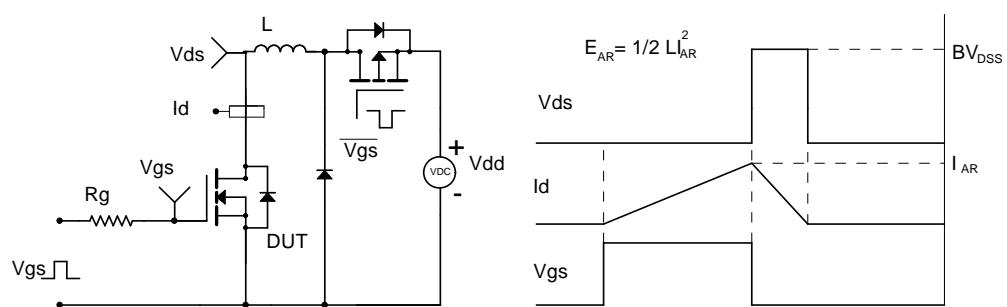
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

